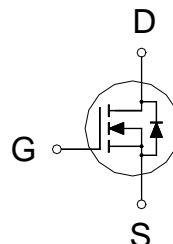


NIKO-SEM

N-Channel Enhancement Mode Field Effect Transistor P0260ETF:TO-220F
P0260ETFS:TO-220FS
Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
600V	4.3Ω	2A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	2	A
		1.3	
Pulsed Drain Current ^{1, 2}	I_{DM}	8	A
Avalanche Current ³	I_{AS}	2	
Avalanche Energy ³	E_{AS}	20	mJ
Power Dissipation	P_D	29	W
		11	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	4.3	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed³ $V_{DD} = 50V$, $L = 10mH$, starting $T_J = 25^\circ C$ **ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	600			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600V, V_{GS} = 0V, T_C = 25^\circ C$			1	μA
		$V_{DS} = 480V, V_{GS} = 0V, T_C = 100^\circ C$			10	

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Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 1A		3.4	4.3	Ω
Forward Transconductance ¹	g _f	V _{DS} = 15V, I _D = 2A		4		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		322		pF
Output Capacitance	C _{oss}			41		
Reverse Transfer Capacitance	C _{rss}			9		
Total Gate Charge ²	Q _g			10.7		nC
Gate-Source Charge ²	Q _{gs}			1.4		
Gate-Drain Charge ²	Q _{gd}			4.8		
Turn-On Delay Time ²	t _{d(on)}			30		nS
Rise Time ²	t _r			61		
Turn-Off Delay Time ²	t _{d(off)}			59		
Fall Time ²	t _f			67		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current ³	I _S				2	A
Forward Voltage ¹	V _{SD}	I _F = 2A, V _{GS} = 0V			1.5	V
Reverse Recovery Time	t _{rr}	I _F = 2A, dI _F /dt = 100A / μS		295		nS
Reverse Recovery Charge	Q _{rr}			1.2		uC

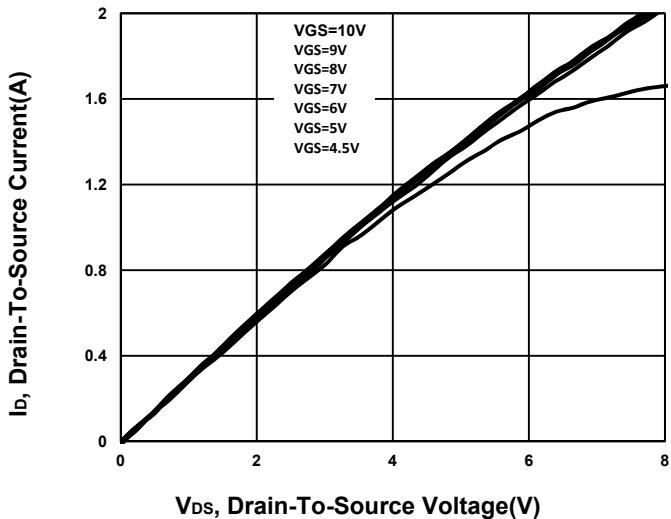
¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

NIKO-SEM

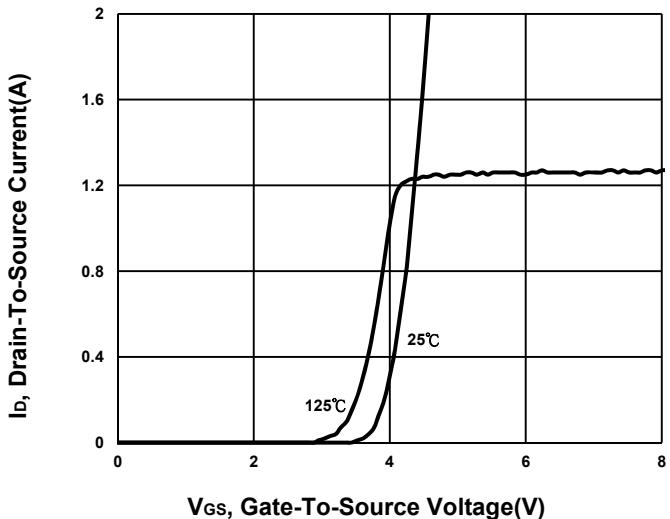
N-Channel Enhancement Mode Field Effect Transistor

**P0260ETF:TO-220F
P0260ETFS:TO-220FS
Halogen-Free & Lead-Free**

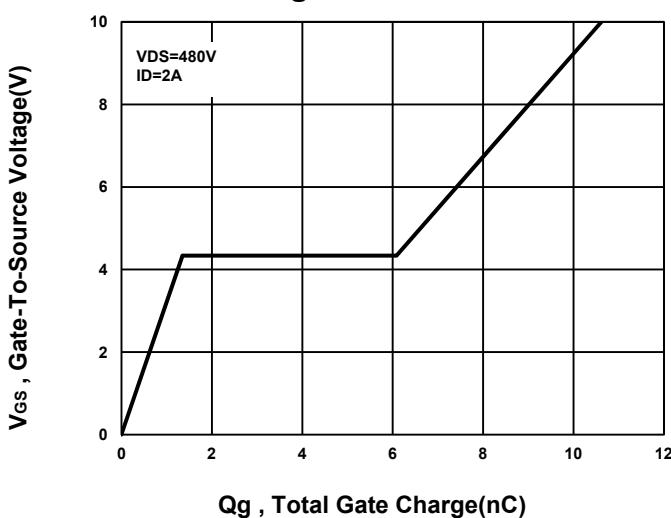
Output Characteristics



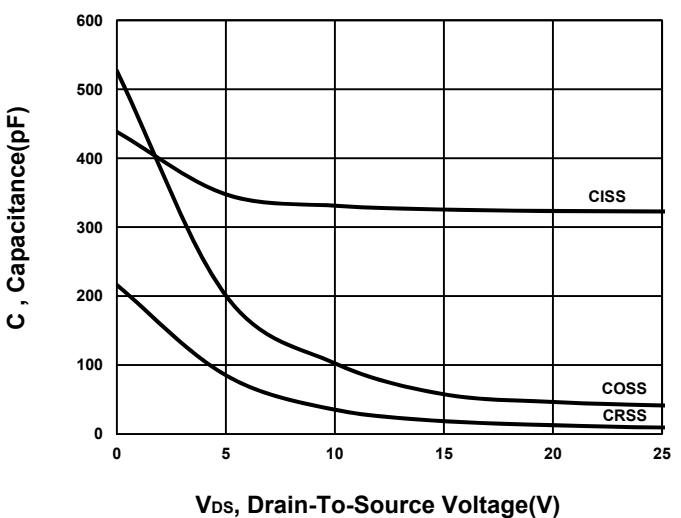
Transfer Characteristics



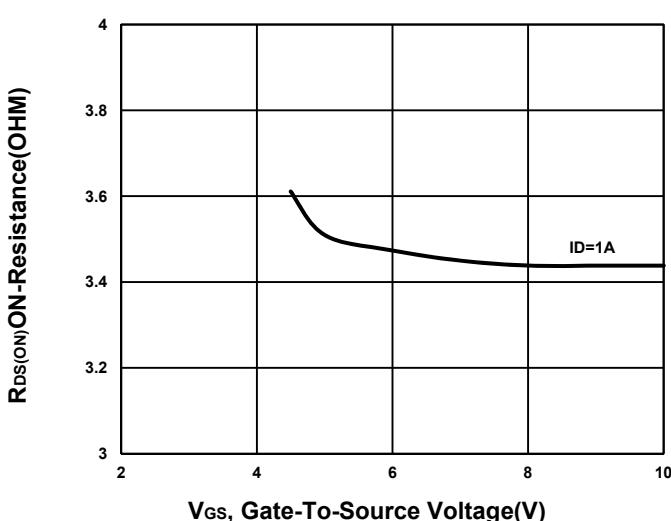
Gate charge Characteristics



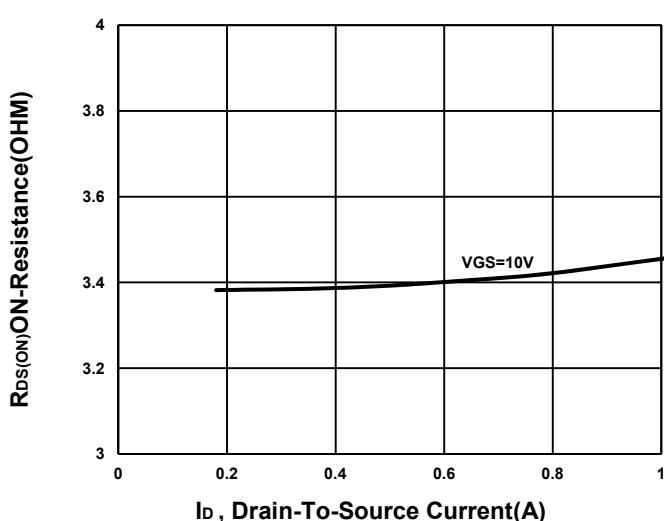
Capacitance Characteristic



On-Resistance VS Gate-To-Source



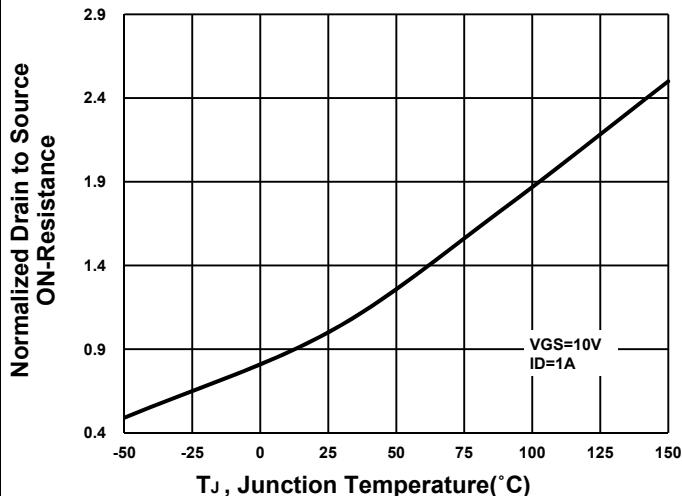
On-Resistance VS Drain Current



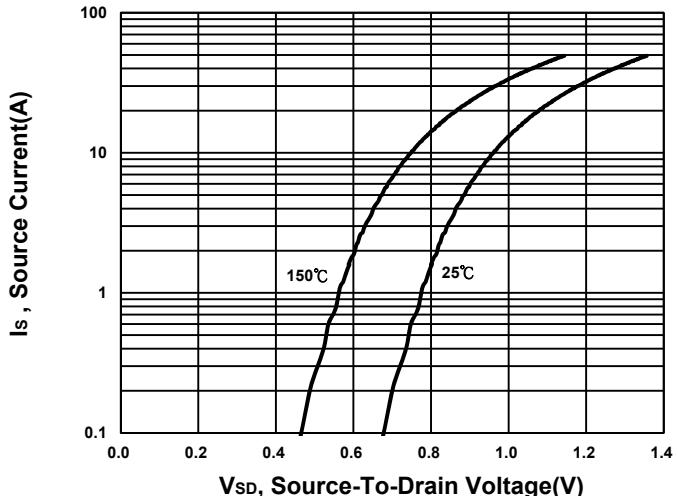
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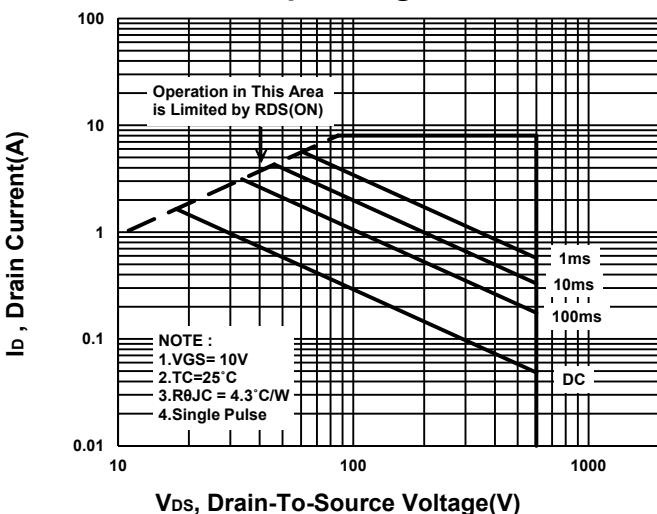
On-Resistance VS Temperature



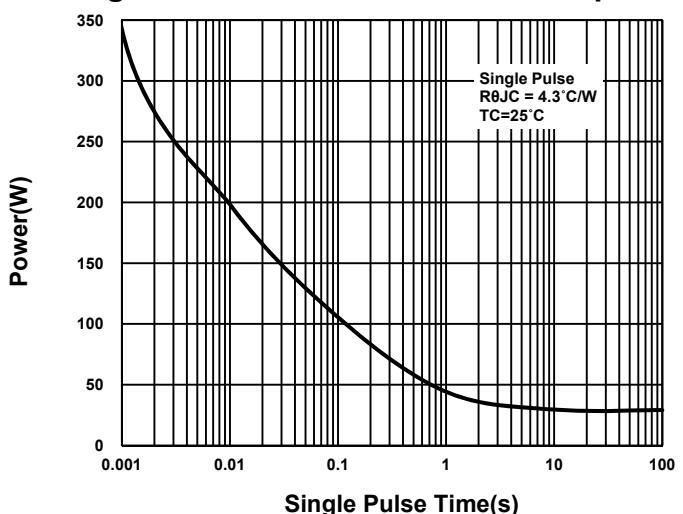
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

